







SN54AHCT573, SN74AHCT573

SCLS243P - OCTOBER 1995 - REVISED APRIL 2024

SNx4AHCT573 Octal Transparent D-Type Latches With 3-State Outputs

1 Features

- Inputs are TTL-voltage compatible
- Latch-up performance exceeds 250mA per JESD 17
- On products compliant to MIL-PRF-38535, all parameters are tested unless otherwise noted. On all other products, production processing does not necessarily include testing of all parameters.

2 Applications

- Servers
- PCs and notebooks
- **Network switches**
- Wearable health and fitness devices
- Telecom infrastructures
- Electronic points-of-sale

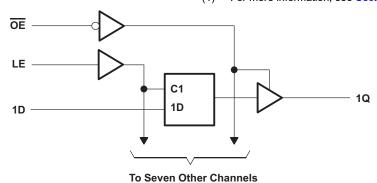
3 Description

The SNx4AHCT573 devices are octal transparent Dtype latches. When the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When LE is low, the Q outputs are latched at the logic levels of the D inputs.

Device Information

PART NUMBER	RATING ⁽¹⁾	PACKAGE ⁽¹⁾
		DB (SSOP, 20)
SN74AHCT573		DGV (TVSOP, 20)
	Catalog	DW (SOIC, 20)
		N (PDIP, 20)
		PW (TSSOP, 20)
CNEAN IOTEZO	Militon	J (CDIP, 20)
SN54AHCT573	Military	W (CFP, 20)

For more information, see Section 11.



Simplified Schematic

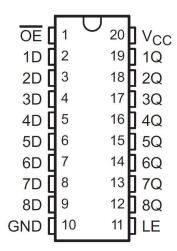


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4 Pin Configuration and Functions



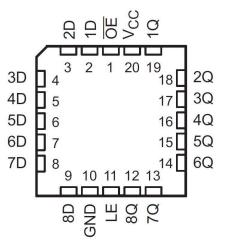


Figure 4-1. SN54AHCT573 J or W Package SN74AHCT573 DB, DGV, DW, N, NS, or PW Package (Top View)

Figure 4-2. SN54AHCT573 FK Package (Top View)

Table 4-1. Pin Functions

Р	IN	TYPE ⁽¹⁾	DESCRIPTION
NO.	NAME	I TPE(")	DESCRIPTION
1	ŌĒ	I	Output Enable
2	1D	I	1D Input
3	2D	I	2D Input
4	3D	I	3D Input
5	4D	I	4D Input
6	5D	I	5D Input
7	6D	I	6D Input
8	7D	I	7D Input
9	8D	I	8D Input
10	GND	_	Ground
11	LE	I	Latch Enable
12	8Q	0	8Q Output
13	7Q	0	7Q Output
14	6Q	0	6Q Output
15	5Q	0	5Q Output
16	4Q	0	4Q Output
17	3Q	0	3Q Output
18	2Q	0	2Q Output
19	1Q	0	1Q Output
20	V _{CC}	_	Power Pin

(1) I = input, O = output

5 Specifications

5.1 Absolute Maximum Ratings⁽¹⁾

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V _{CC}	Supply voltage range		-0.5	7	V
VI	Input voltage range ⁽²⁾		-0.5	7	V
Vo	Output voltage range ⁽²⁾		-0.5	V _{CC} + 0.5	V
I _{IK}	Input clamp current	V _I < 0		-20	mA
I _{OK}	Output clamp current	$V_O < 0$ or $V_O > V_{CC}$		±20	mA
Io	Continuous output current	$V_O = 0$ to V_{CC}		±25	mA
	Continuous current through V _{CC} or GND			±75	mA
T _J	Junction temperature			150	°C
T _{stg}	Storage temperature		-65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

5.2 ESD Ratings

			MIN	MAX	UNIT
V	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾		±2000	\/
V _(ESD)	Electrostatic discriarge	Charged-device model (CDM), per ANSI/ESDA/JEDEC JS-002 ⁽²⁾		±1000	v

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)(1)

		SN54AH0	SN54AHCT573		T573	UNIT
		MIN	MAX	MIN	MIN MAX	
V _{CC}	Supply voltage	4.5	5.5	4.5	5.5	V
V _{IH}	High-level input voltage	2		2		V
V _{IL}	Low-level input voltage		0.8		0.8	V
VI	Input voltage	0	5.5	0	5.5	V
Vo	Output voltage	0	V _{CC}	0	V _{CC}	V
I _{OH}	High-level output current		-8		-8	mA
I _{OL}	Low-level output current		8		8	mA
Δt/Δν	Input transition rise or fall rate		20		20	ns/V
T _A	Operating free-air temperature	-55	125	-40	125	°C

All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs (SCBA004).

⁽²⁾ The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



5.4 Thermal Information

		SN74AHCT573							
	THERMAL METRIC ⁽¹⁾	DW	DB	DGV	N	NS	PW	UNIT	
		20 PINS							
$R_{\theta JA}$	Junction-to-ambient thermal resistance	79.4	97.9	117.2	53.3	79.2	103.3		
R ₀ JC(top)	Junction-to-case (top) thermal resistance	45.7	59.6	32.7	40.0	45.7	37.8		
$R_{\theta JB}$	Junction-to-board thermal resistance	46.9	53.1	58.7	34.2	46.8	54.3	°C/W	
ΨЈТ	Junction-to-top characterization parameter	18.7	21.3	1.15	26.4	19.3	2.9	C/VV	
Ψ_{JB}	Junction-to-board characterization parameter	46.5	52.7	58.0	34.1	46.4	53.8		
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	n/a	n/a	n/a	n/a	n/a	n/a		

⁽¹⁾ For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report (SPRA953).

5.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{cc}	T _A = 25°C			-55°C to 125°C SN54AHCT573		-40°C to 85°C SN74AHCT573		-40°C to 125°C SN74AHCT573		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
V	I _{OH} = -50 μA	4.5V	4.4	4.5		4.4		4.4		4.4		V
V _{OH}	I _{OH} = -8mA	4.50	3.94			3.8		3.8		3.8	3.8	v
V	I _{OL} = 50 μA	4.5V			0.1		0.1		0.1		0.1	V
V _{OL}	I _{OL} = 8mA	4.50			0.36		0.44		0.44		0.44	V
I _I	V _I = 5.5V or GND	0V to 5.5V			±0.1		±1 ⁽¹⁾		±1		±2	μA
I _{OZ}	V _O = V _{CC} or GND	5.5V			±0.25		±2.5		±2.5		±2.5	μA
I _{CC}	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5V			4		40		40		40	μA
ΔI _{CC} ⁽²⁾	One input at 3.4V, Other inputs at V _{CC} or GND	5.5V			1.35		1.5		1.5		1.5	mA
Ci	V _I = V _{CC} or GND	5V		2.5	10				10		10	pF
Co	V _O = V _{CC} or GND	5V		3								pF

5.6 Timing Requirements

over recommended operating free-air temperature range, V_{CC} = 5V ± 0.5V (unless otherwise noted) (see Section 6)

PARAMETER		T _A = 2	T _A = 25°C		-55°C to 125°C SN54AHCT573		-40°C to 85°C SN74AHCT573		-40°C to 125°C SN74AHCT573	
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _w	Pulse duration, LE high	5		5		5		5		ns
t _{su}	Setup time, data before LE↓	3.5		3.5		3.5		3.5		ns
t _h	Hold time, data after LE↓	1.5		1.5		1.5		1.5		ns

On products compliant to MIL-PRF-38535, this parameter is not production tested at V_{CC} = 0V. This is the increase in supply current for each input at one of the specified TTL voltage levels, rather than 0V or V_{CC} .



5.7 Switching Characteristics, SNx4AHCT573

over recommended operating free-air temperature range, V_{CC} = 5V ± 0.5V (unless otherwise noted) (see Section 6)

PARAMETER	FROM	то	T _A =	25°C		T _A = -40°C to	o 85°C	T _A = -40°C to	125°C	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII	
C _L = 15pF	C _L = 15pF										
t _{pd}	D	Q		5.1	7	1	9	1	9.5	ns	
t _{pd}	LE	Q		5.6	7.5	1	9	1	9.5	ns	
t _{en}	ŌĒ	Q		5.5	7.5	1	10	1	11	ns	
t _{dis}	ŌĒ	Q		5.5	8	1	11	1	12	ns	
C _L = 50pF				,	·						
t _{pd}	D	Q		6.1	8	1	10	1	10.5	ns	
t _{pd}	LE	Q		6.6	8.5	1	10	1	10.5	ns	
t _{en}	ŌĒ	Q		6.5	8.5	1	11	1	11.5	ns	
t _{dis}	ŌĒ	Q		6.7	9	1	12	1	12.5	ns	
t _{sk(o)}				,	1.5		1.5			ns	

- (1) On products compliant to MIL-PRF-38535, this parameter is not production tested.
- (2) On products compliant to MIL-PRF-38535, this parameter does not apply.

5.8 Switching Characteristics, SN54AHCT573

over recommended operating free-air temperature range, V_{CC} = 5V ± 0.5V (unless otherwise noted) (see Section 6)

PARAMETER	FROM TO		T _A = 29	T _A = 25°C			T _A = -55°C to 125°C		
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	UNIT	
C _L = 15pF									
t _{pd}	D	Q	5	.1 ⁽¹⁾	7 ⁽¹⁾	1 ⁽¹⁾	9(1)	ns	
t _{pd}	LE	Q	5	.6 ⁽¹⁾	7.5 ⁽¹⁾	1 ⁽¹⁾	9 ⁽¹⁾	ns	
t _{en}	ŌĒ	Q	5	.5 ⁽¹⁾	7.5 ⁽¹⁾	1 ⁽¹⁾	9 ⁽¹⁾	ns	
t _{dis}	ŌĒ	Q	5	.5 ⁽¹⁾	8 ⁽¹⁾	1 ⁽¹⁾	11 ⁽¹⁾	ns	
C _L = 50pF	•								
t _{pd}	D	Q		6.1	8	1	10	ns	
t _{pd}	LE	Q		6.6	8.5	1	10	ns	
t _{en}	ŌĒ	Q		6.5	8.5	1	11	ns	
t _{dis}	ŌĒ	Q		6.7	9	1	12	ns	
t _{sk(o)}					1.5 ⁽²⁾	-		ns	

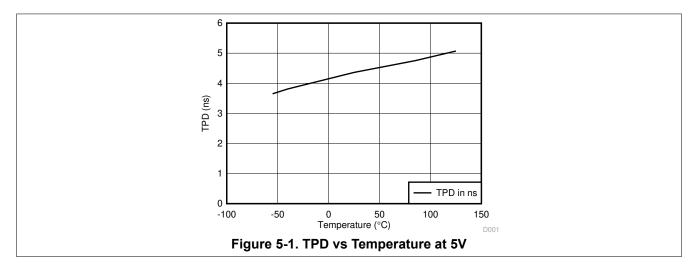
5.9 Operating Characteristics

 $V_{CC} = 5V, T_A = 25^{\circ}C$

PARAMETER		TEST CO	TYP	UNIT	
C _{pd}	Power dissipation capacitance	No load,	f = 1MHz	16	pF



5.10 Typical Characteristics

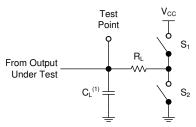


6 Parameter Measurement Information

Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1MHz, $Z_O = 50\Omega$, $R_L = 1k\Omega$, $t_t < 3ns$, $V_t = 1.5V$.

For clock inputs, f_{max} is measured when the input duty cycle is 50%.

The outputs are measured one at a time with one input transition per measurement.



(1) C_L includes probe and test-fixture capacitance.

Figure 6-1. Load Circuit for 3-State Outputs

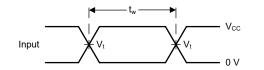


Figure 6-2. Voltage Waveforms, Pulse Duration

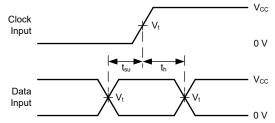
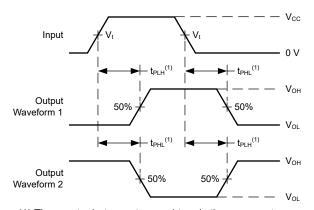
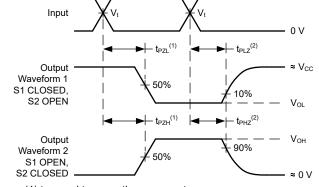


Figure 6-3. Voltage Waveforms, Setup and Hold Times



 V_{CC}



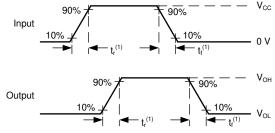


- (1) The greater between t_{PLH} and t_{PHL} is the same as t_{pd} .
- Figure 6-4. Voltage Waveforms, Propagation Delays
- (1) t_{PLZ} and t_{PHZ} are the same as t_{dis} .

(2) t_{PZL} and t_{PZH} are the same as t_{en}.

Figure 6-5. Voltage Waveforms, Propagation

Delays for 3-State Outputs



(1) The greater between t_r and t_f is the same as t_f.

Figure 6-6. Voltage Waveforms, Input and Output Transition Times

7 Detailed Description

7.1 Overview

The SNx4AHCT573 devices are octal transparent D-type latches. When the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When LE is low, the Q outputs are latched at the logic levels of the D inputs.

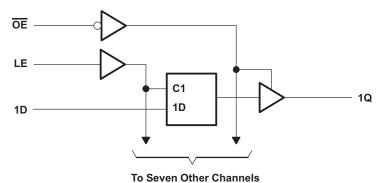
A buffered output-enable (\overline{OE}) input can be used to place the eight outputs in either a normal logic state (high or low) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pull-up components.

To put the device in the high-impedance state during power up or power down, tie \overline{OE} to V_{CC} through a pull-up resistor; the current-sinking capability of the driver determines the minimum value of the resistor.

 $\overline{\text{OE}}$ does not affect the internal operations of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.



7.2 Functional Block Diagram



7.3 Feature Description

- TTL inputs
 - Lowered switching threshold allows up translation 3.3V to 5V
- · Slow edges reduce output ringing

7.4 Device Functional Modes

Table 7-1. Function Table (Each Latch)

	INPUTS	OUTPUT					
ŌĒ	LE	D	Q				
L	Н	Н	Н				
L	Н	L	L				
L	L	Χ	Q_0				
Н	Χ	Χ	Z				

8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

The SN74AHCT573 is a low-drive CMOS device that can be used for a multitude of bus interface type applications where output ringing is a concern. The low drive and slow edge rates will minimize overshoot and undershoot on the outputs. The input switching levels have been lowered to accommodate TTL inputs of $0.8V\,V_{IL}$ and $2V\,V_{IH}$. This feature makes the device an excellent choice for translating up from $3.3V\,$ to $5V.\,$ Figure 8-2 shows this type of translation.

8.2 Typical Application

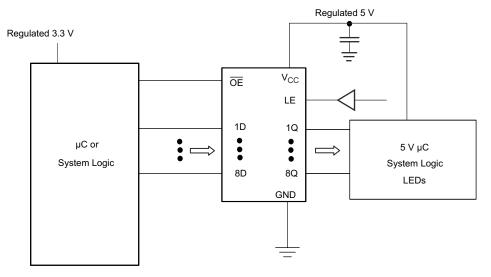


Figure 8-1. Typical Application Schematic

8.2.1 Design Requirements

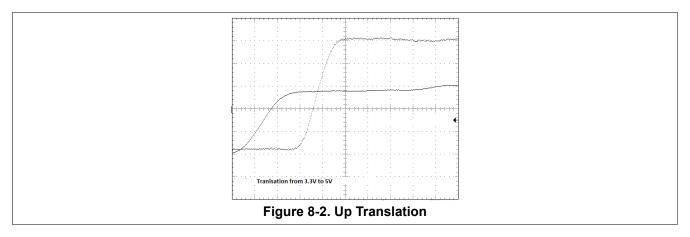
This device uses CMOS technology and has balanced output drive. Take care to avoid bus contention because it can drive currents that would exceed maximum limits. The high drive will also create fast edges into light loads; therefore, routing and load conditions should be considered to prevent ringing.

8.2.2 Detailed Design Procedure

- 1. Recommended input conditions:
 - Rise time and fall time specs: See (Δt/ΔV) in the Recommended Operating Conditions table.
 - Specified High and low levels: See (V_{IH} and V_{IL}) in the Recommended Operating Conditions table.
 - Inputs are overvoltage tolerant allowing them to go as high as 5.5V at any valid V_{CC}.
- 2. Recommend output conditions
 - Load currents should not exceed 25mA per output and 75mA total for the part.
 - Outputs should not be pulled above V_{CC}.



8.2.3 Application Curves



8.3 Power Supply Recommendations

The power supply can be any voltage between the MIN and MAX supply voltage rating located in the *Recommended Operating Conditions* table.

Each V_{CC} pin should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, $0.1\mu F$ bypass capacitor is recommended. If there are multiple V_{CC} pins, $0.01\mu F$ or $0.022\mu F$ is recommended for each power pin. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. A $0.1\mu F$ and $1\mu F$ are commonly used in parallel. The bypass capacitor should be installed as close to the power pin as possible for best results.

8.4 Layout

8.4.1 Layout Guidelines

When using multiple bit logic devices inputs should never float.

In many cases, functions or parts of functions of digital logic devices are unused (for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used). Such input pins should not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. Figure 8-3 specifies the rules that must be observed under all circumstances.

All unused inputs of digital logic devices must be connected to a high or low bias to prevent them from floating. The logic level that should be applied to any particular unused input depends on the function of the device. Generally they will be tied to GND or V_{CC} ; whichever makes more sense or is more convenient. It is generally acceptable to float outputs unless the part is a transceiver. If the transceiver has an output enable pin, then it will disable the outputs section of the part when asserted. This will not disable the input section of the IOs so they cannot float when disabled.

8.4.2 Layout Example

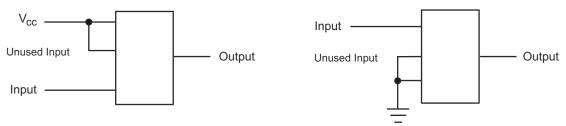


Figure 8-3. Layout Diagram



9 Device and Documentation Support

9.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.2 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

9.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

9.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

C	hanges from Revision O (July 2014) to Revision P (April 2024)	Page
•	Moved storage temperature from Handling Ratings table to Absolute Maximum Ratings table	4
•	Changed Handling Ratings table to ESD Ratings table	4
•	Added temperature range column labels in Electrical Characteristics table	5
•	Added temperature range column labels in Timing Requirements table	5
	Changed t _{PLH} and t _{PHL} to be t _{pd} , t _{PZH} and t _{PZL} to be t _{en} , and t _{PLZ} and t _{PHZ} to be t _{dis}	
	Changed Switching Characteristics table to be two tables separating military and catalog	
	device characteristics	6
•	Changed parameter measurement information section images and tables to improve clarity and upda	ate
	formatting	<mark>7</mark>

Cr	nanges from Revision N (July 2003) to Revision O (July 2014)	Page
•	Updated document to new TI data sheet format	1
•	Deleted Ordering Information table	1
•	Added Military Disclaimer to Features list	1
	Added Applications	
	Added Pin Functions table	
•	Added Handling Ratings table	4
	Changed MAX operating temperature to 125°C in Recommended Operating Conditions table	
•	Added Thermal Information table	5
•	Added -40°C to 125°C temperature range for SNx4AHCT573 in Electrical Characteristics table	5
	, g	

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•	Added –40°C to 125°C temperature range for SNx4AHCT573 in Timing Requirements table	5
	Added Typical Characteristics	
	Added Application and Implementation section1	
	Added Power Supply Recommendations and Layout sections	
	, ,	

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

2-Apr-2024

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PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
5962-9685501QRA	ACTIVE	CDIP	J	20	20	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-9685501QR A SNJ54AHCT573J	Samples
5962-9685501QSA	ACTIVE	CFP	W	20	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-9685501QS A SNJ54AHCT573W	Samples
SN74AHCT573DBR	ACTIVE	SSOP	DB	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HB573	Samples
SN74AHCT573DGVR	ACTIVE	TVSOP	DGV	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HB573	Samples
SN74AHCT573DW	LIFEBUY	SOIC	DW	20	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT573	
SN74AHCT573DWR	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT573	Samples
SN74AHCT573N	ACTIVE	PDIP	N	20	20	RoHS & Green	NIPDAU	N / A for Pkg Type	-40 to 125	SN74AHCT573N	Samples
SN74AHCT573PWR	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-40 to 125	HB573	Samples
SN74AHCT573PWRE4	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HB573	Samples
SN74AHCT573PWRG4	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HB573	Samples
SNJ54AHCT573J	ACTIVE	CDIP	J	20	20	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-9685501QR A SNJ54AHCT573J	Samples
SNJ54AHCT573W	ACTIVE	CFP	W	20	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-9685501QS A SNJ54AHCT573W	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

PACKAGE OPTION ADDENDUM

www.ti.com 2-Apr-2024

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF SN54AHCT573, SN74AHCT573:

Catalog: SN74AHCT573

Military: SN54AHCT573

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





	-
A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AHCT573DBR	SSOP	DB	20	2000	330.0	16.4	8.2	7.5	2.5	12.0	16.0	Q1
SN74AHCT573DGVR	TVSOP	DGV	20	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74AHCT573DWR	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
SN74AHCT573PWR	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
SN74AHCT573PWRG4	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1



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*All dimensions are nominal

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Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74AHCT573DBR	SSOP	DB	20	2000	356.0	356.0	35.0
SN74AHCT573DGVR	TVSOP	DGV	20	2000	356.0	356.0	35.0
SN74AHCT573DWR	SOIC	DW	20	2000	367.0	367.0	45.0
SN74AHCT573PWR	TSSOP	PW	20	2000	356.0	356.0	35.0
SN74AHCT573PWRG4	TSSOP	PW	20	2000	356.0	356.0	35.0

PACKAGE MATERIALS INFORMATION

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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
5962-9685501QSA	W	CFP	20	25	506.98	26.16	6220	NA
SN74AHCT573DW	DW	SOIC	20	25	507	12.83	5080	6.6
SN74AHCT573N	N	PDIP	20	20	506	13.97	11230	4.32
SNJ54AHCT573W	W	CFP	20	25	506.98	26.16	6220	NA

W (R-GDFP-F20)

CERAMIC DUAL FLATPACK



- A. All linear dimensions are in inches (millimeters).
- This drawing is subject to change without notice.
- C. This package can be hermetically sealed with a ceramic lid using glass frit.

 D. Index point is provided on cap for terminal identification only.

 E. Falls within Mil—Std 1835 GDFP2—F20







- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



PW (R-PDSO-G20)

PLASTIC SMALL OUTLINE



- All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
 C. Publication IPC-7351 is recommended for alternate design.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.







- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-150.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



14 LEADS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

DGV (R-PDSO-G**)

24 PINS SHOWN

PLASTIC SMALL-OUTLINE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15 per side.

D. Falls within JEDEC: 24/48 Pins – MO-153 14/16/20/56 Pins – MO-194

N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.





SOIC



- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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